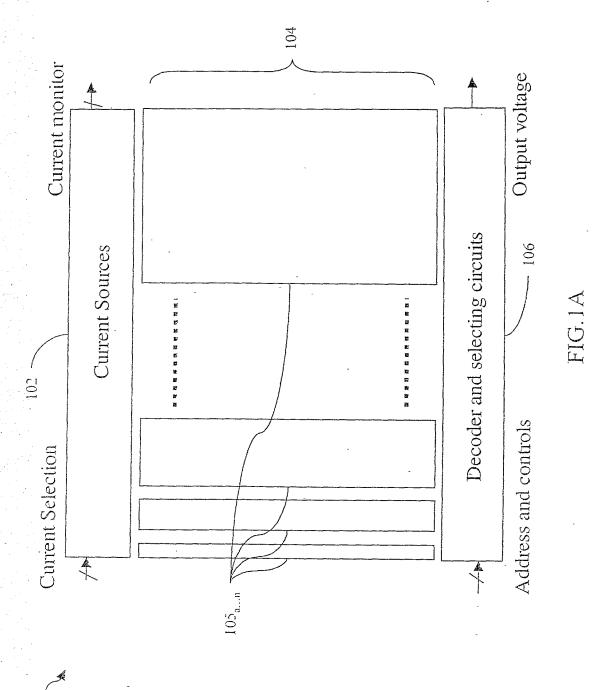
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Page 1 of 10

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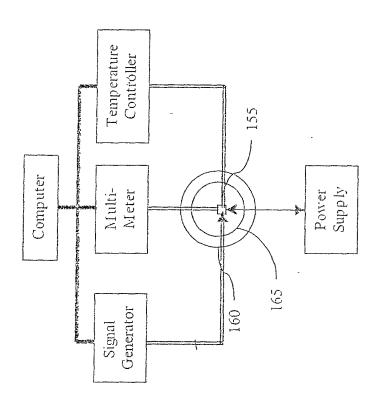
Title: AN INTEGRATED ELECTRÓMIGRATION LENGTH EFFECT TESTING METHOD AND APPARATUS Filed: February 22, 2002

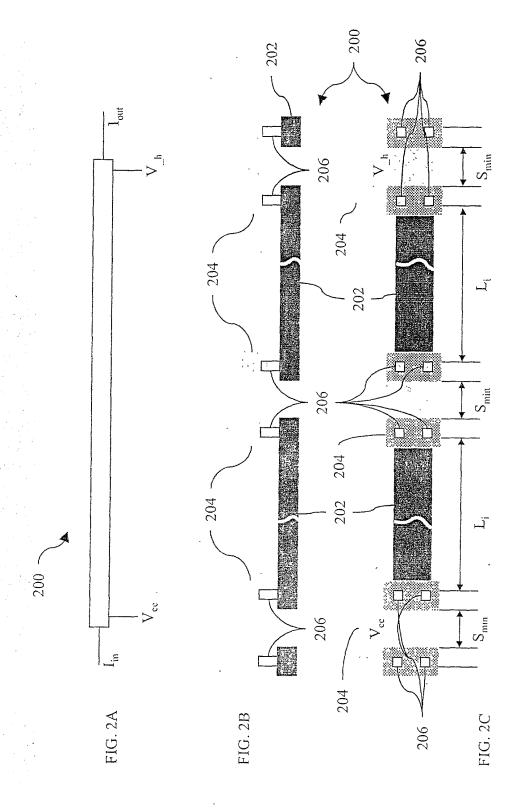
Inventor: Wei Zhang Docket No.: SUN-P6557

Page 2 of 10

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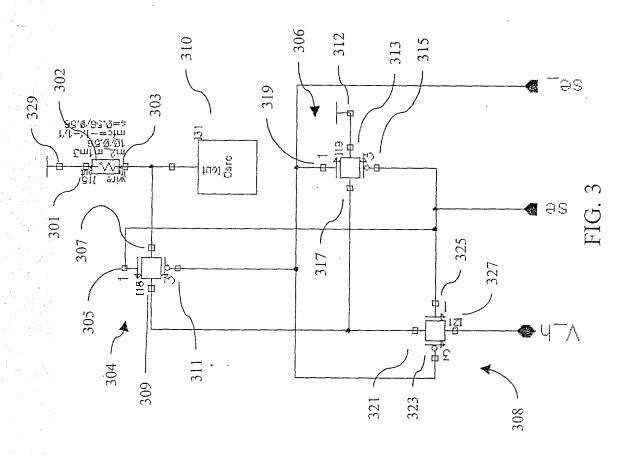


Filed: February 22, 2002

Inventor: Wei Zhang Docket No.: SUN-P6557 Page 4 of 10

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Filed: February 22, 2002

Inventor: Wei Zhang Docket No.: SUN-P6557

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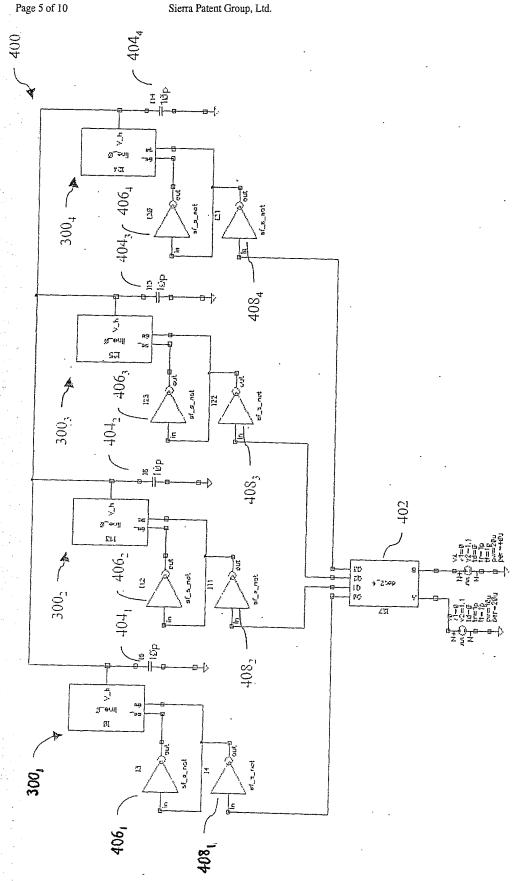
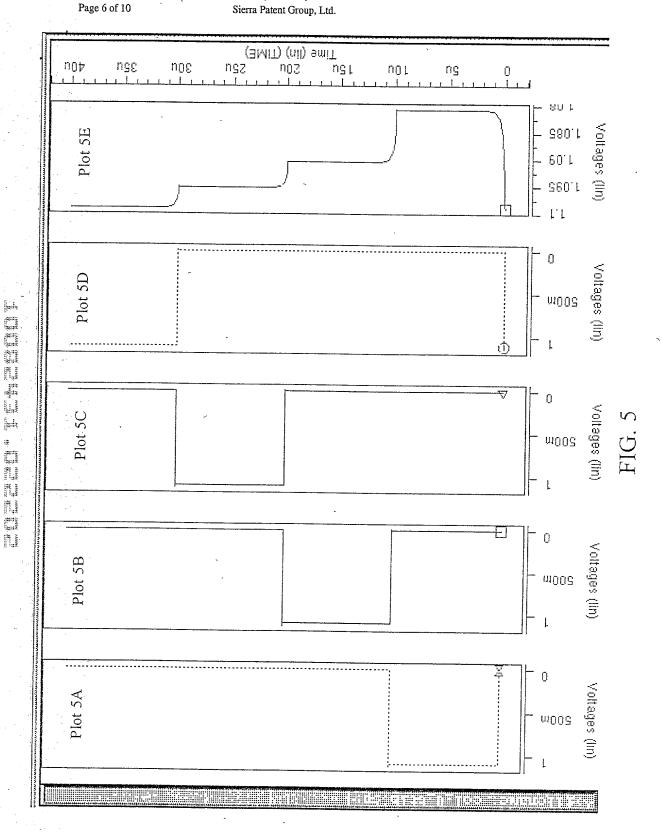


FIG. 4

Title: AN INTEGRATED ELECTROMIGRATION LENGTH EFFECT TESTING METHOD AND APPARATUS

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Inventor: Wei Zhang Docket No.: SUN-P6557 Express mail: ET533056828US Attorney: Timothy A. Brisson Sierra Patent Group, Ltd.



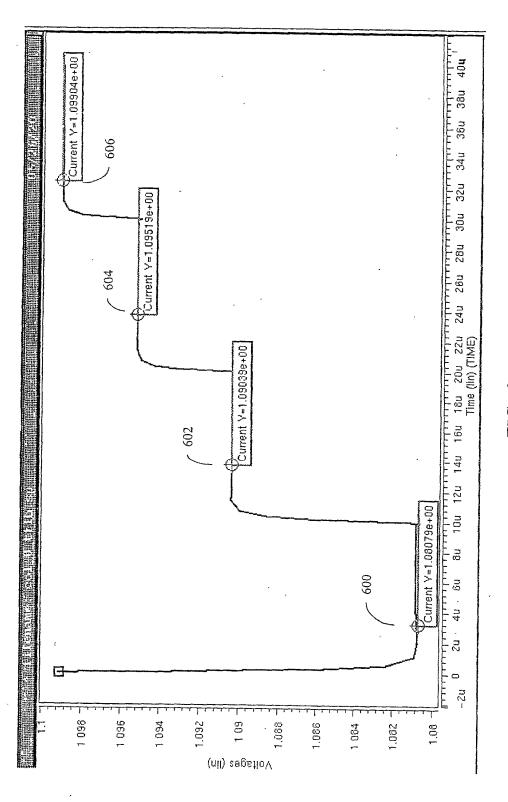


FIG. (

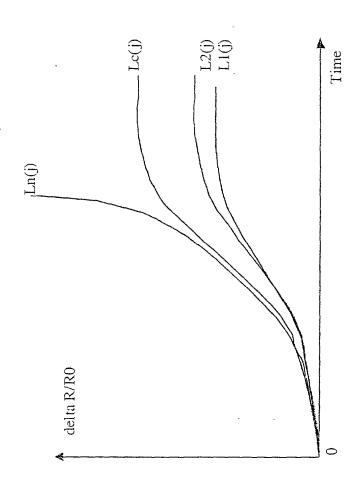
Filed: February 22, 2002

Inventor: Wei Zhang Docket No.: SUN-P6557

Page 8 of 10

Express mail: ET533056828US Attorney: Timothy A. Brisson

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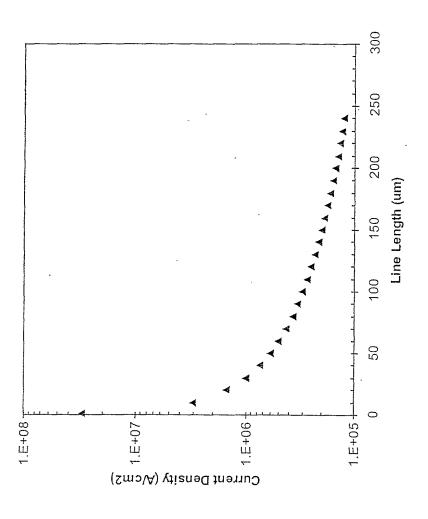


FIG. 8

Inventor: Wei Zhang Docket No.: SUN-P6557

Express mail: ET533056828US Attorney: Timothy A. Brisson Sierra Patent Group, Ltd.

Page 10 of 10

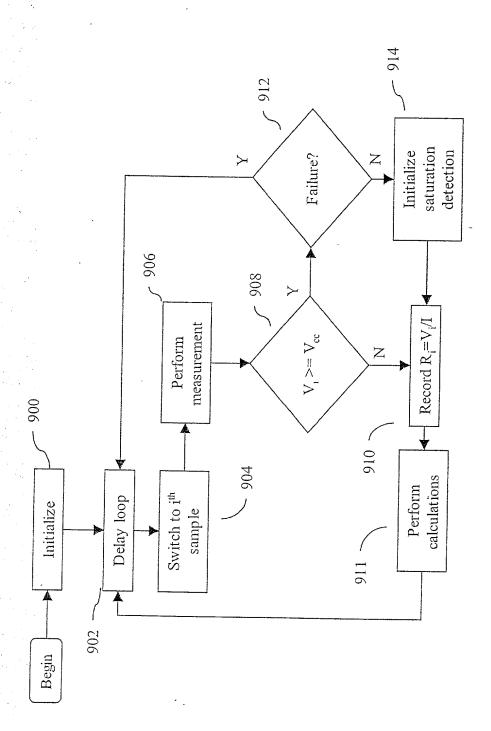


FIG. (